# MOSFET – Power, Single, N-Channel, DPAK/IPAK 30 V, 58 A

#### **Features**

- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- AEC Q101 Qualified NVD4809N
- These Devices are Pb-Free and are RoHS Compliant

#### **Applications**

- CPU Power Delivery
- DC-DC Converters
- Low Side Switching

#### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltag	Drain-to-Source Voltage			30	V
Gate-to-Source Voltag	е		$V_{GS}$	±20	V
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	13.1	Α
Current (R <sub>θJA</sub> ) (Note 1)		T <sub>A</sub> = 85°C		10.1	
Power Dissipation (R <sub>θJA</sub> ) (Note 1)		T <sub>A</sub> = 25°C	P <sub>D</sub>	2.63	W
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	9.6	Α
Current (R <sub>θJA</sub> ) (Note 2)	Steady	T <sub>A</sub> = 85°C		7.4	
Power Dissipation (R <sub>0</sub> JA) (Note 2)	State	T <sub>A</sub> = 25°C	P <sub>D</sub>	1.4	W
Continuous Drain		T <sub>C</sub> = 25°C	I <sub>D</sub>	58	Α
Current (R <sub>θJC</sub> ) (Note 1)		T <sub>C</sub> = 85°C		45	
Power Dissipation ( $R_{\theta JC}$ ) (Note 1)		T <sub>C</sub> = 25°C	P <sub>D</sub>	52	W
Pulsed Drain Current	t <sub>p</sub> =10μs	T <sub>A</sub> = 25°C	I <sub>DM</sub>	130	Α
Current Limited by Pack	age	T <sub>A</sub> = 25°C	I <sub>DmaxPkg</sub>	45	Α
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>stg</sub>	–55 to 175	°C
Source Current (Body Diode)			I <sub>S</sub>	43	Α
Drain to Source dV/dt			dV/dt	6.0	V/ns
Single Pulse Drain-to–Source Avalanche Energy ( $V_{DD}$ = 24 V, $V_{GS}$ = 10 V, L = 1.0 mH, $I_{L(pk)}$ = 13.5 A, $R_{G}$ = 25 $\Omega$ )			E <sub>AS</sub>	91.0	mJ
Lead Temperature for So (1/8" from case for 10 s)	ldering Pu	rposes	T <sub>L</sub>	260	°C

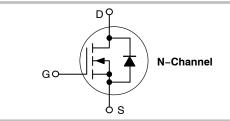
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



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V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub> MAX	I <sub>D</sub> MAX
30 V	9.0 mΩ @ 10 V	58 A
30 V	14 mΩ @ 4.5 V	30 A







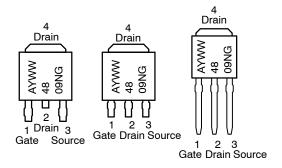


IPAK CASE 369AD (Straight Lead) STYLE 2



IPAK
CASE 369D
(Straight Lead
DPAK) STYLE 2

# MARKING DIAGRAMS & PIN ASSIGNMENTS



A = Assembly Location\*

Y = Year WW = Work Week 4809N = Device Code G = Pb-Free Package

\* The Assembly Location code (A) is front side optional. In cases where the Assembly Location is stamped in the package, the front side assembly code may be blank.

#### **ORDERING INFORMATION**

See detailed ordering and shipping information in the package dimensions section on page 6 of this data sheet.

#### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	2.9	°C/W
Junction-to-TAB (Drain)	$R_{\theta JC-TAB}$	3.5	
Junction-to-Ambient - Steady State (Note 1)	$R_{\theta JA}$	57.1	
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	107.2	

#### **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter	Symbol	Test Co	ndition	Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /T <sub>J</sub>				25		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C			1.0	μΑ
		$V_{DS} = 24 \text{ V}$	T <sub>J</sub> = 125°C			10	
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V	GS = ±20 V			±100	nA
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}$	D = 250 μA	1.5		2.5	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				5.7		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 to	I <sub>D</sub> = 30 A		7.0	9.0	mΩ
		11.5 V	I <sub>D</sub> = 15 A		7.0		7
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 30 A		12	14	
			I <sub>D</sub> = 15 A		11		7
Forward Transconductance	gFS	V <sub>DS</sub> = 15 V	, I <sub>D</sub> = 15 A		9.0		S
CHARGES AND CAPACITANCES							
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 \text{ V, f} = 1.0 \text{ MHz,}$ $V_{DS} = 12 \text{ V}$			1456		pF
Output Capacitance	C <sub>oss</sub>				315		7
Reverse Transfer Capacitance	C <sub>rss</sub>				200		
Total Gate Charge	Q <sub>G(TOT)</sub>				11	13	nC
Threshold Gate Charge	Q <sub>G(TH)</sub>	V <sub>GS</sub> = 4.5 V,	V <sub>DS</sub> = 15 V,		2.5		
Gate-to-Source Charge	$Q_{GS}$	I <sub>D</sub> = 3			4.8		
Gate-to-Drain Charge	$Q_{GD}$				5.0		
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 11.5 V, I <sub>D</sub> = 3			25		nC
SWITCHING CHARACTERISTICS (Note 4)						•	•
Turn-On Delay Time	t <sub>d(on)</sub>				12.3		ns
Rise Time	t <sub>r</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 15 V,			21.3		
Turn-Off Delay Time	t <sub>d(off)</sub>	I <sub>D</sub> = 15 A, F			15.1		
Fall Time	t <sub>f</sub>				5.3		

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

3. Pulse Test: Pulse Width ≤ 300 µs, Duty Cycle ≤ 2%.

Surface-mounted on FR4 board using 1 in sq pad size, 1 oz Cu.
 Surface-mounted on FR4 board using the minimum recommended pad size.

<sup>4.</sup> Switching characteristics are independent of operating junction temperatures.

**Test Condition** 

Min

Тур

Max

Unit

#### **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise noted) (continued)

i didilictei	Cyllibol	1631 00	nanion	IVIIII	קעי	IVIGA	0
Turn-On Delay Time	t <sub>d(on)</sub>				7.0		ns
Rise Time	t <sub>r</sub>	V <sub>GS</sub> = 11.5 V, V <sub>DS</sub> = 15 V,			22.7		
Turn-Off Delay Time	t <sub>d(off)</sub>	I <sub>D</sub> = 15 A, F			25.3		
Fall Time	t <sub>f</sub>		•		2.8		
DRAIN-SOURCE DIODE CHARACTE	RISTICS						
Forward Diode Voltage	$V_{SD}$	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C		0.95	1.2	V
		I <sub>S</sub> = 30 A	T <sub>J</sub> = 125°C		0.83		
Reverse Recovery Time	t <sub>RR</sub>		•		19.5		ns
Charge Time	ta	$V_{GS}$ = 0 V, dls/dt = 100 A/ $\mu$ s, $I_{S}$ = 30 A			10.7		
Discharge Time	tb				8.8		
Reverse Recovery Time	$Q_{RR}$				9.2		nC
PACKAGE PARASITIC VALUES							
Source Inductance	L <sub>S</sub>				2.49		nΗ
Drain Inductance, DPAK	L <sub>D</sub>		•		0.0164		
Drain Inductance, IPAK	L <sub>D</sub>	$T_A = 2$	25°C		1.88		
Gate Inductance	L <sub>G</sub>				3.46		
Gate Resistance	$R_{G}$		•		2.4		Ω

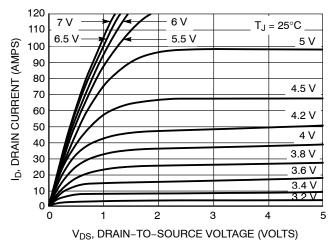
Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

3. Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.

4. Switching characteristics are independent of operating junction temperatures.

Parameter

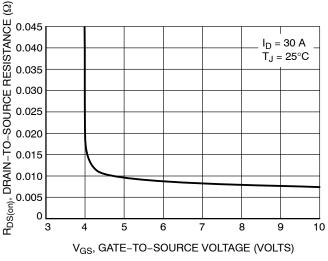
#### TYPICAL PERFORMANCE CURVES



120  $V_{DS} \ge 10 \text{ V}$ DRAIN CURRENT (AMPS) 100 80 60 40 T<sub>J</sub> = 125°C  $T_J = 25^{\circ}C$ ۵ 20  $T_J = -55^{\circ}C$ 0 5 0 3 6 V<sub>GS</sub>, GATE-TO-SOURCE VOLTAGE (VOLTS)

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



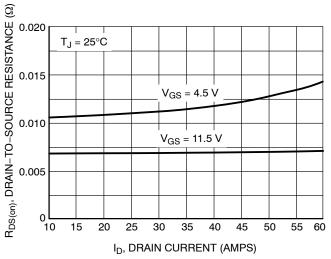
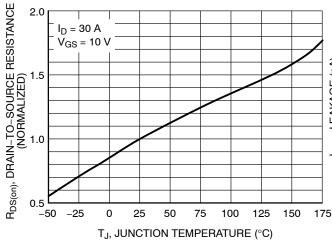


Figure 3. On–Resistance vs. Gate–to–Source Voltage

Figure 4. On-Resistance vs. Drain Current and Gate Voltage



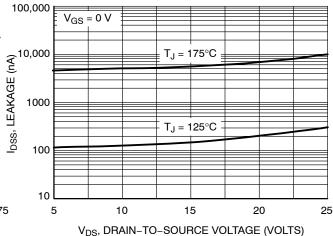
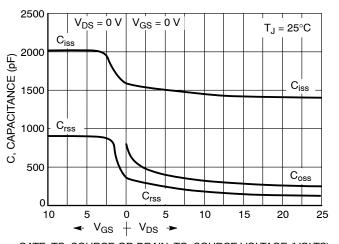


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Drain Voltage

#### **TYPICAL PERFORMANCE CURVES**



GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (VOLTS)

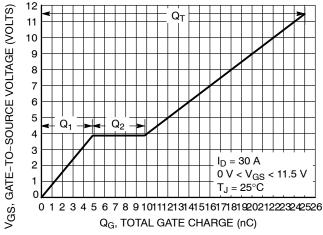


Figure 8. Gate-To-Source and Drain-To-Source Voltage vs. Total Charge



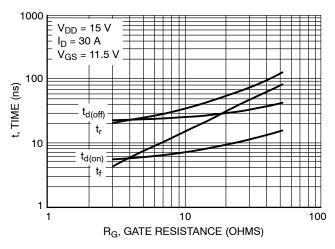


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

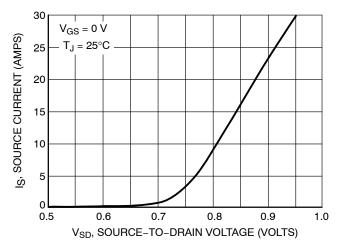


Figure 10. Diode Forward Voltage vs. Current

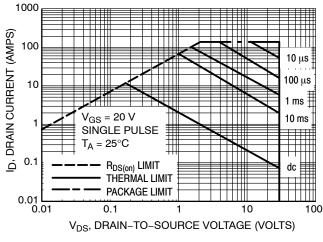


Figure 11. Maximum Rated Forward Biased Safe Operating Area

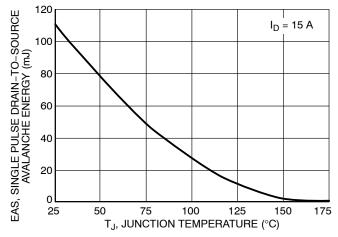


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

#### **TYPICAL PERFORMANCE CURVES**

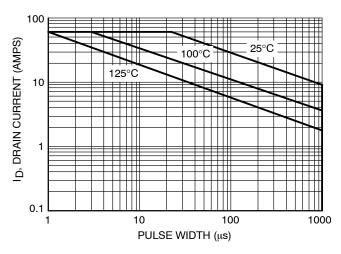


Figure 13. Avalanche Characteristics

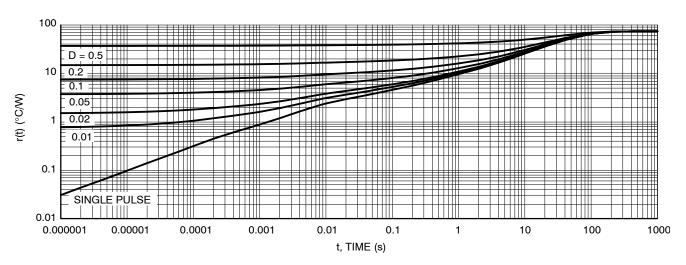


Figure 14. Thermal Response

#### **ORDERING INFORMATION**

Order Number	Package	Shipping <sup>†</sup>
NTD4809NT4G	DPAK (Pb-Free)	2500 / Tape & Reel
NTD4809N-1G	IPAK (Pb-Free)	75 Units/Rail
NTD4809N-35G	IPAK Trimmed Lead (3.5 ± 0.15 mm) (Pb-Free)	75 Units/Rail
NVD4809NT4G	DPAK (Pb-Free)	2500 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

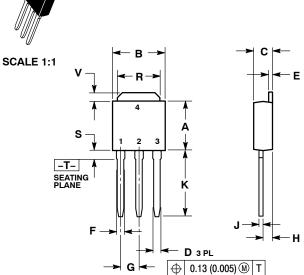
# **MECHANICAL CASE OUTLINE**

**PACKAGE DIMENSIONS** 





**DATE 15 DEC 2010** 



STYLE 2:

PIN 1. GATE

3

STYLE 6: PIN 1. MT1 2. MT2 3. GATE

2. DRAIN

4. DRAIN

MT2

SOURCE

STYLE 1: PIN 1. BASE

3

STYLE 5: PIN 1. GATE

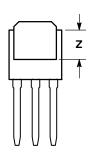
2. ANODE 3. CATHODE

ANODE

2. COLLECTOR

**EMITTER** 

COLLECTOR



#### NOTES:

- DIMENSIONING AND TOLERANCING PER
- ANSI Y14.5M, 1982.
  2. CONTROLLING DIMENSION: INCH.

	INCHES		MILLIM	ETERS
DIM	MIN	MAX	MIN	MAX
Α	0.235	0.245	5.97	6.35
В	0.250	0.265	6.35	6.73
С	0.086	0.094	2.19	2.38
D	0.027	0.035	0.69	0.88
Е	0.018	0.023	0.46	0.58
F	0.037	0.045	0.94	1.14
G	0.090	BSC	2.29	BSC
Н	0.034	0.040	0.87	1.01
J	0.018	0.023	0.46	0.58
Κ	0.350	0.380	8.89	9.65
R	0.180	0.215	4.45	5.45
S	0.025	0.040	0.63	1.01
٧	0.035	0.050	0.89	1.27
Z	0.155		3.93	

#### **MARKING DIAGRAMS**

STYLE 4: PIN 1. CATHODE

STYLE 3: PIN 1. ANODE

2. CATHODE

4. CATHODE

3 ANODE

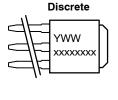
STYLE 7: PIN 1. GATE 2. COLLECTOR

3. EMITTER

COLLECTOR

ANODE
 GATE

4. ANODE





xxxxxxxxx = Device Code Α = Assembly Location IL = Wafer Lot

Υ = Year WW = Work Week

DOCUMENT NUMBER:	98AON10528D	Electronic versions are uncontrolled except when accessed directly from Printed versions are uncontrolled except when stamped "CONTROLLED	
DESCRIPTION:	IPAK (DPAK INSERTION MOUNT)		PAGE 1 OF 1

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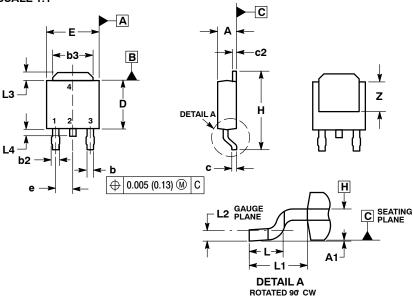


**DATE 03 JUN 2010** 

#### NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- 2. CONTROLLING DIMENSION: INCHES.
  3. THERMAL PAD CONTOUR OPTIONAL WITHIN DI-MENSIONS b3, L3 and Z.
  4. DIMENSIONS D AND E DO NOT INCLUDE MOLD
- FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE
- DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 6. DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.

	INC	HES	MILLIN	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.086	0.094	2.18	2.38
A1	0.000	0.005	0.00	0.13
b	0.025	0.035	0.63	0.89
b2	0.030	0.045	0.76	1.14
b3	0.180	0.215	4.57	5.46
С	0.018	0.024	0.46	0.61
c2	0.018	0.024	0.46	0.61
D	0.235	0.245	5.97	6.22
E	0.250	0.265	6.35	6.73
е	0.090	BSC	2.29	BSC
Н	0.370	0.410	9.40	10.41
L	0.055	0.070	1.40	1.78
L1	0.108	REF	2.74	REF
L2	0.020	BSC	0.51	BSC
L3	0.035	0.050	0.89	1.27
L4		0.040		1.01
Z	0.155		3.93	



#### STYLE 1: PIN 1. BASE 2. COLLECTOR 3. EMITTER 4. COLLECTOR

PIN 1. GATE 2. ANODE 3. CATHODE

4. ANODE

STYLE 5:

STYLE 2: PIN 1. GATE 2. DRAIN 3. SOURCE 4. DRAIN

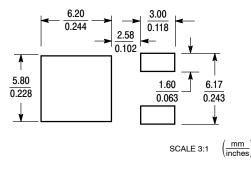
STYLE 3: PIN 1. ANODE 2. CATHODE 3. ANODE CATHODE STYLE 4: PIN 1. CATHODE 2. ANODE 3. GATE

STYLE 6: PIN 1. MT1 2. MT2

3. GATE

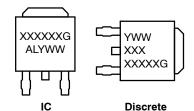
STYLE 7: PIN 1. GATE 2. COLLECTOR 3. EMITTER COLLECTOR

### **SOLDERING FOOTPRINT\***



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

#### **GENERIC** MARKING DIAGRAM\*



XXXXXX = Device Code Α = Assembly Location L = Wafer Lot ٧ = Year = Work Week WW = Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking.

DOCUMENT NUMBER:	98AON13126D	AON13126D Electronic versions are uncontrolled except when accessed directly from the Docum Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in r	
DESCRIPTION:	DPAK (SINGLE GAUGE)		PAGE 1 OF 1

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## **MECHANICAL CASE OUTLINE**

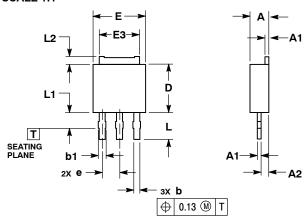


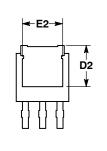
#### 3.5 MM IPAK, STRAIGHT LEAD

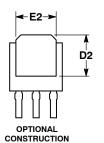
CASE 369AD **ISSUE B** 

**DATE 18 APR 2013** 









- NOTES:
  1.. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. 2.. CONTROLLING DIMENSION: MILLIMETERS.
- DIMENSION b APPLIES TO PLATED TERMINAL AND IS MEASURED BETWEEN 0.15 AND 0.30mm FROM TERMINAL TIP.
- DIMENSIONS D AND E DO NOT INCLUDE MOLD GATE OR MOLD FLASH.

	MILLIMETERS		
DIM	MIN	MAX	
Α	2.19	2.38	
A1	0.46	0.60	
A2	0.87	1.10	
b	0.69	0.89	
b1	0.77	1.10	
D	5.97	6.22	
D2	4.80		
E	6.35	6.73	
E2	4.57	5.45	
E3	4.45	5.46	
е	2.28 BSC		
L	3.40	3.60	
L1		2.10	
L2	0.89	1.27	

#### **GENERIC MARKING DIAGRAMS\***

# Integrated

STYL	E 1	:
PIN	1.	BA

STYLE 5:

PIN 1. GATE

λSE 2. COLLECTOR 3. **EMITTER** 

ANODE
 CATHODE

ANODE

COLLECTOR

# STYLE 2: PIN 1. GATE

STYLE 6:

PIN 1. MT1

MT2
 GATE

MT2

2. DRAIN 3. SOURCE DRAIN

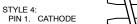
# STYLE 3: PIN 1. ANODE 2. CATHODE

3. ANODE CATHODE

#### STYLE 7: PIN 1. GATE

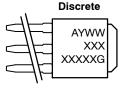
2. COLLECTOR 3. EMITTER

COLLECTOR



2. ANODE 3. GATE

ANODE





XXXXXX = Device Code Α = Assembly Location

L = Wafer Lot Υ = Year WW = Work Week G = Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present.

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DESCRIPTION:	3.5 MM IPAK, STRAIGHT LEAD		PAGE 1 OF 1

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